

Notice of References Cited	Application/Control No. 10/543,172	Applicant(s)/Patent Under Reexamination KII ET AL.	
	Examiner Bai D. Vu	Art Unit 2165	Page 1 of 1

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*	B	US-6,469,239 B1	10-2002	Fukuda, Shinichi	84/602
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NON-PATENT DOCUMENTS

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